

OTA

TEST REPORT

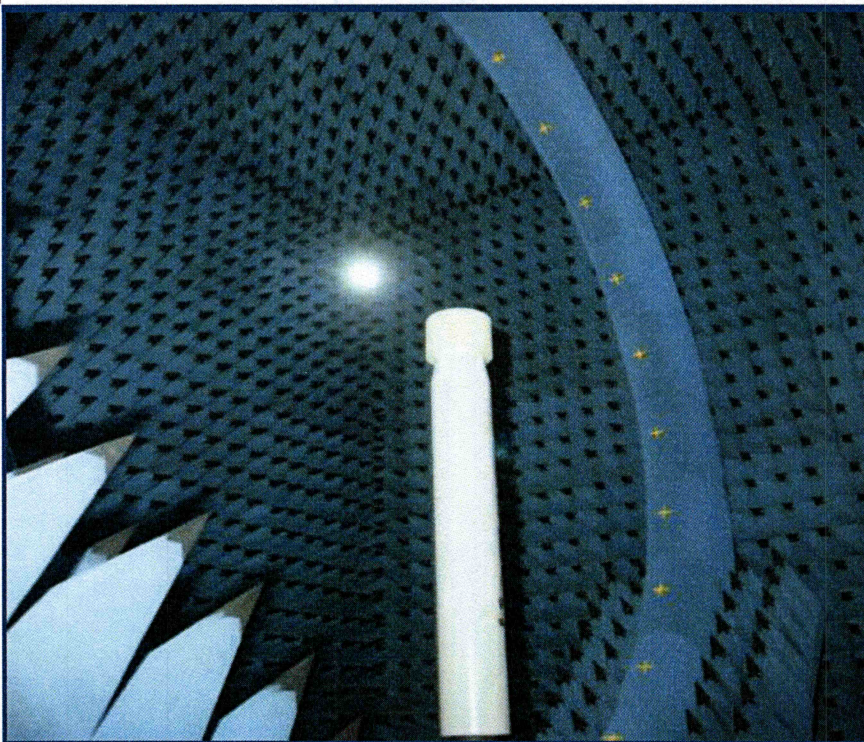
ISSUED BY
Shenzhen BALUN Technology Co., Ltd.



FOR
Antenna

ISSUED TO
SHEN ZHEN HOPE MICROELECTRONICS CO., LIMITED

30/F, Block A, Building 8, Phase 3, Vanke Cloud City, Liuxin 4th street,
XiLi, Nanshan, Shenzhen 518055, China



Tested by: Zong Liyao

Zong Liyao

Date Jul. 23, 2021

Approved by: Liao Jianming

Liao Jianming
(Technical Director)

Date Jul. 23, 2021

Report No: BL-SZ2170362-901

EUT Name: Antenna

Model Name: RFM75C-S3

Brand Name: N/A

Test Standard: ANSI/IEEE Std 149-1979

Maximum: Gain: 0.02 (dBi)

Efficiency: 36%

Test Date: Jul. 09, 2021

Date of Issue: Jul. 23, 2021

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Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Jul. 23, 2021</u>	<u>Initial Issue</u>

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1 Administrative Data (GENERAL INFORMATION)

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6685 0100

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Description	All measurement facilities used to collect the measurement data are located at Block B, FL 1, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China 518055

1.3 Laboratory Condition

Ambient Temperature	19°C to 25°C
Ambient Relative Humidity	45% to 55%
Ambient Pressure	100 kPa to 102 kPa

1.4 Announce

- (1) The test report reference to the report template version v2.2.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (5) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (6) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.
- (7) The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	SHEN ZHEN HOPE MICROELECTRONICS CO., LIMITED
Address	30/F, Block A, Building 8, Phase 3, Vanke Cloud City, Liuxin 4th street, XiLi, Nanshan, Shenzhen 518055, China

2.2 Manufacturer Information

Manufacturer	SHEN ZHEN HOPE MICROELECTRONICS CO., LIMITED
Address	30/F, Block A, Building 8, Phase 3, Vanke Cloud City, Liuxin 4th street, XiLi, Nanshan, Shenzhen 518055, China

2.3 Factory Information

Factory	N/A
Address	N/A

2.4 General Description for Equipment under Test (EUT)

EUT Name	Antenna
Model Name Under Test	RFM75C-S3
Antenna Type	PCB Antenna
Dimensions	12mm×8mm

2.5 Ancillary Equipment

Note: Not Applicable

2.6 Technical Information

Frequency Range	2400MHz~ 2483.5MHz
Test Frequencies	2400MHz, 2410MHz, 2420MHz, 2430MHz, 2440MHz, 2450MHz, 2460MHz, 2470MHz, 2480MHz, 2483.5MHz

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	ANSI/IEEE Std 149-1979	IEEE Standard Test Procedures for Antennas

3.2 Test Verdict

Report Section	Description	Remark
ANNEX A.1	Gain and Efficiency	--
ANNEX B	Radiation Pattern	--

3.3 Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Item	Uncertainty
VSWR(S11)	± 0.61
Gain	$\pm 1.92\text{dB}$

ANNEX A TEST RESULTS

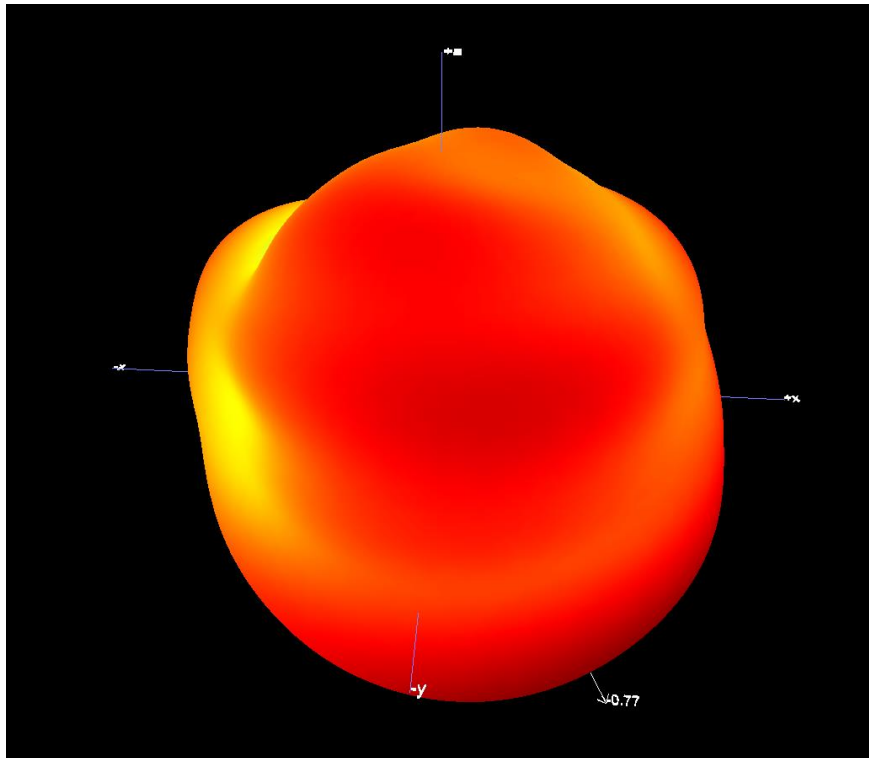
A.1 Gain and Efficiency

Frequency	Gain (dBi)	Efficiency (%)
2400MHz	-0.77	28
2410MHz	-0.38	30
2420MHz	-0.31	31
2430MHz	-0.24	32
2440MHz	-0.19	33
2450MHz	-0.22	33
2460MHz	-0.22	34
2470MHz	-0.10	35
2480MHz	0.02	36
2483.5MHz	0.02	36

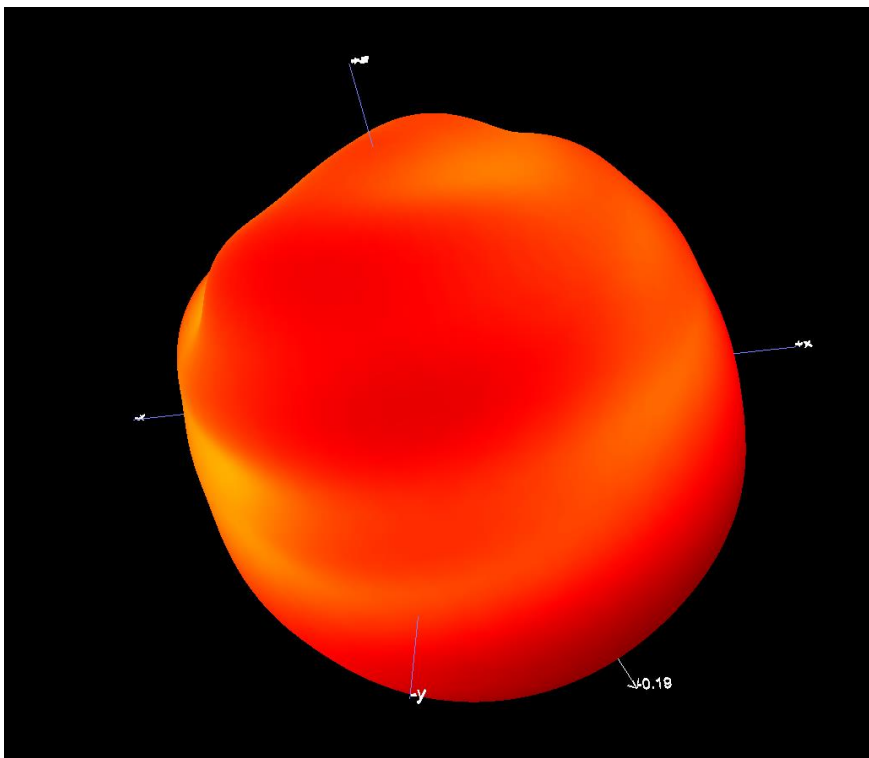
ANNEX B RADIATION PATTERN

3D Pattern

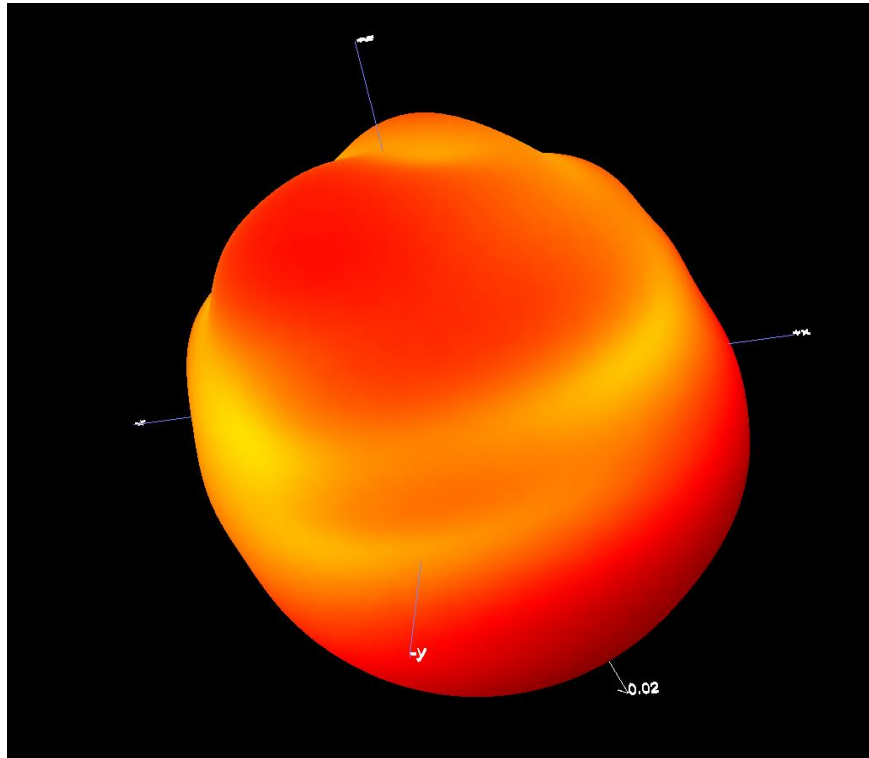
B.1.1 2400MHz



B.1.2 2440MHz

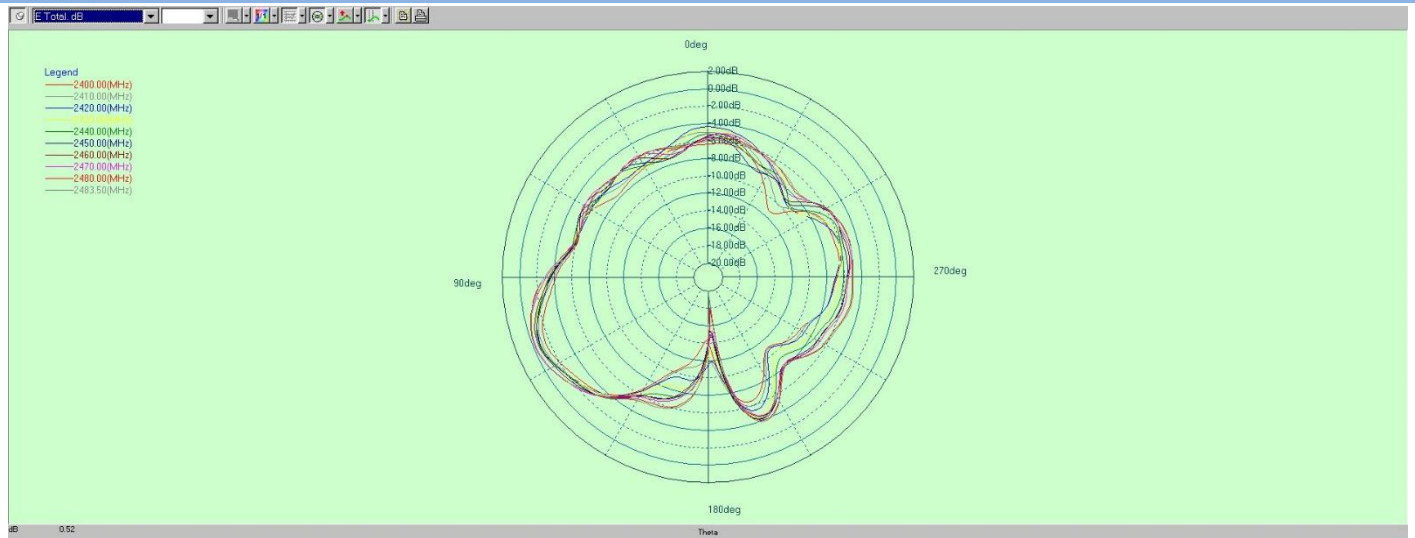


B.1.3 2483.5MHz

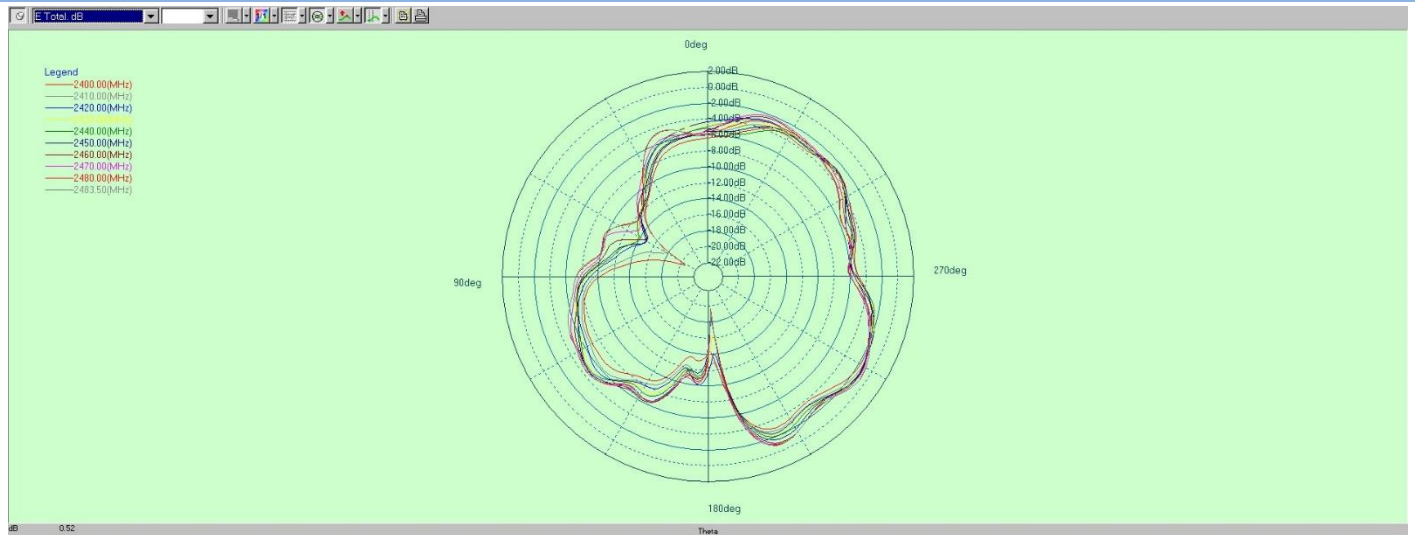


B.2 1D Radiation Pattern

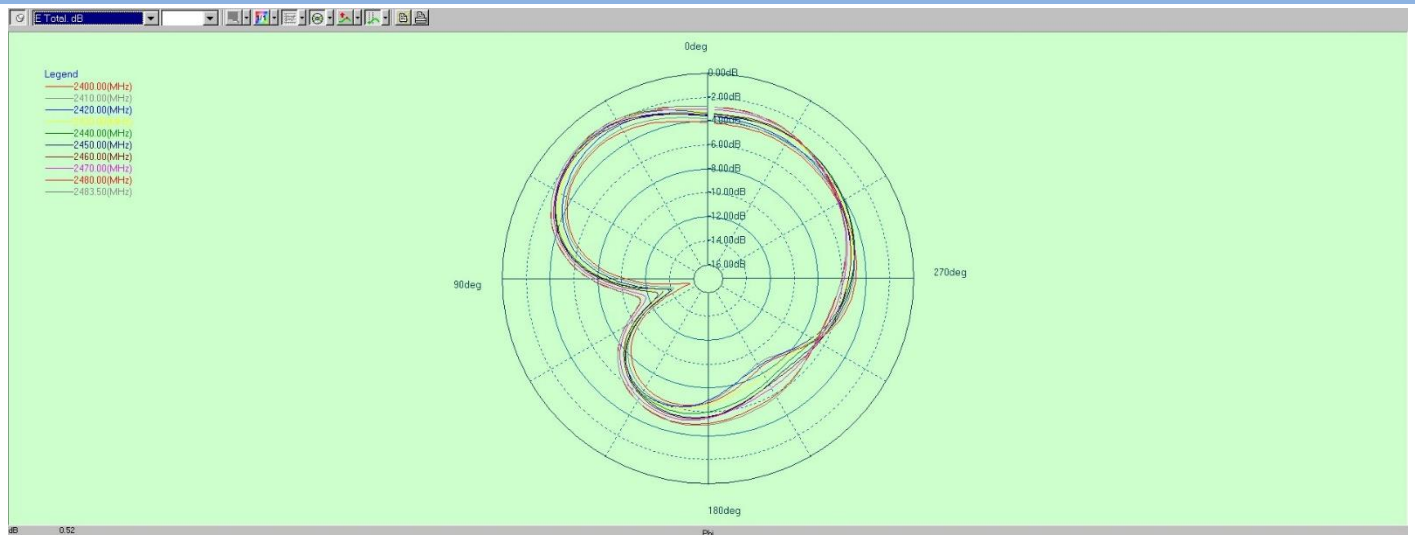
B2.1 PHI=0



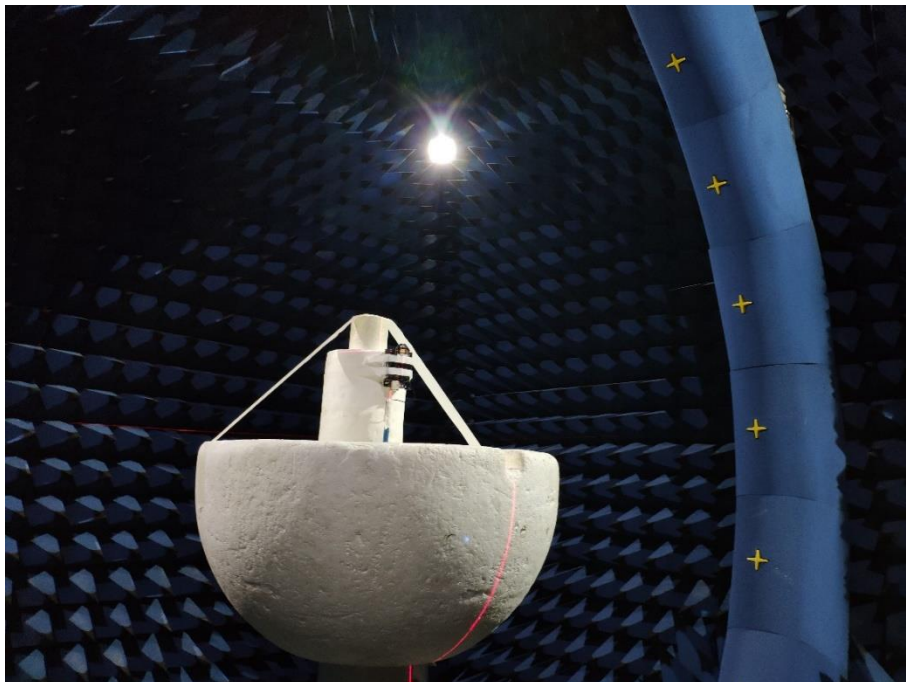
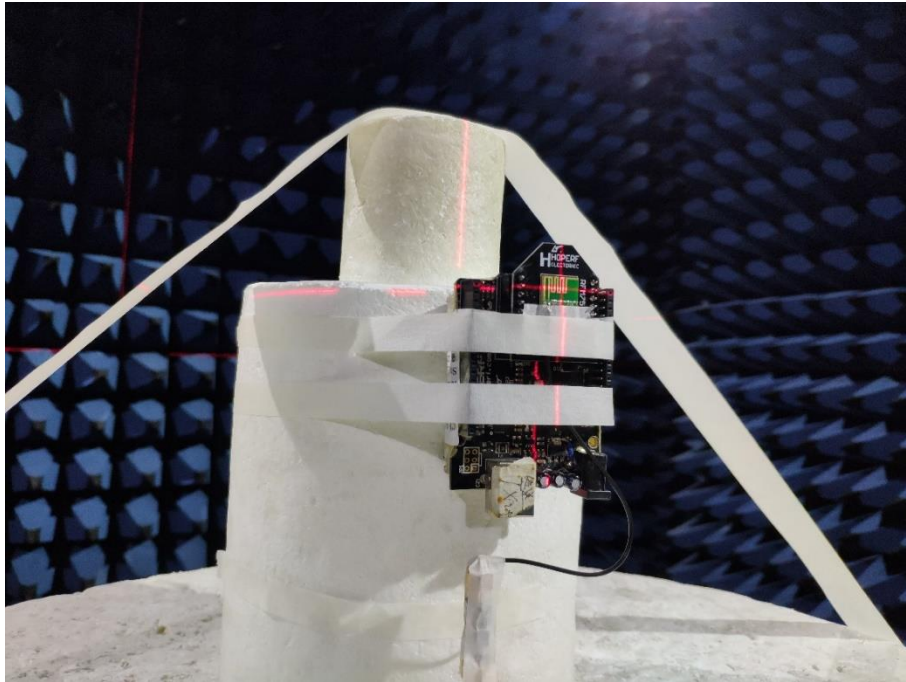
B2.2 PHI=90



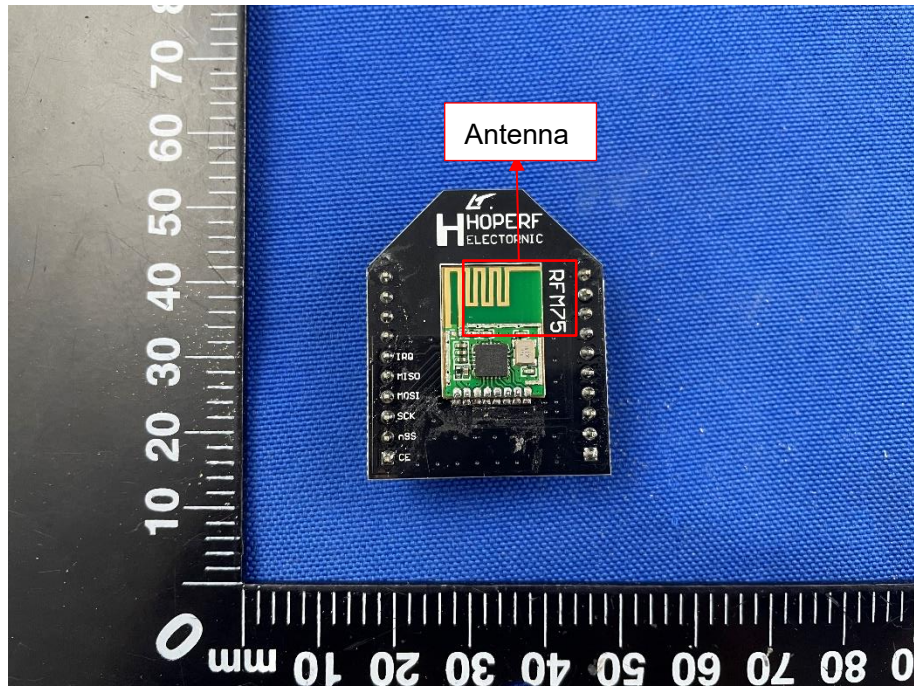
B2.3 THETA=90



ANNEX C TEST SETUP PHOTO



ANNEX D EUT PHOTO



--END OF REPORT--